# **MOSFET** - Power, Single

## **N-Channel**

80 V, 29 mΩ, 22 A

## **NVTFS6H880NL**

#### **Features**

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- NVTFS6H880NLWF Wettable Flanks Product
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	80	V
Gate-to-Source Voltage	9		$V_{GS}$	±20	٧
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	22	Α
Current R <sub>θJC</sub> (Notes 1, 2, 3, 4)	Steady	T <sub>C</sub> = 100°C		15	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	33	W
R <sub>θJC</sub> (Notes 1, 2, 3)		T <sub>C</sub> = 100°C		17	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	6.6	Α
Current R <sub>θJA</sub> (Notes 1, 3, 4)	Steady	T <sub>A</sub> = 100°C		4.7	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	3.1	W
R <sub>θJA</sub> (Notes 1, 3)	T <sub>A</sub> = 100°C		1.5		
Pulsed Drain Current	$T_A = 25$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	83	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	28	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 1 A)			E <sub>AS</sub>	70	mJ
Lead Temperature for S (1/8" from case for 10 s)		urposes	TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 3)	$R_{ heta JC}$	4.6	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	49	

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Psi  $(\Psi)$  is used as required per JESD51-12 for packages in which substantially less than 100% of the heat flows to single case surface.
- 3. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

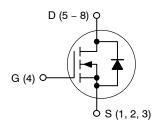


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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
80 V	29 mΩ @ 10 V	00.4	
	38 mΩ @ 4.5 V	22 A	

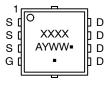
#### N-Channel



#### MARKING DIAGRAMS



WDFN8 (μ8FL) CASE 511AB





WDFNW8 (Full-Cut μ8FL) CASE 515AN



XXXX = Specific Device Code A = Assembly Location

Y = Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

### **ELECTRICAL CHARACTERISTICS** ( $T_J = 25$ °C unless otherwise noted)

Parameter	Symbol	Test Cond	ition	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•		•		•		•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		80			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 \text{ V},$ $T_J = 25^{\circ}\text{C}$				10	μΑ
			T <sub>J</sub> = 125°C			100	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{G}$	<sub>S</sub> = 20 V			100	nA
ON CHARACTERISTICS (Note 5)	1				•		•
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 20 μA	1.2		2.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.2		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 5 A		24	29	mΩ
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 5 A		30	38	mΩ
Forward Transconductance	9FS	V <sub>DS</sub> = 8 V, I <sub>D</sub>	= 10 A		31		S
CHARGES, CAPACITANCES & GATE	RESISTANCE					•	•
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 40 V			431		
Output Capacitance	C <sub>OSS</sub>				56		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				4		
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 40 V; I <sub>D</sub> = 10 A			9		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 40 V; I <sub>D</sub> = 10A			1		
Gate-to-Source Charge	Q <sub>GS</sub>				1.7		
Gate-to-Drain Charge	$Q_{GD}$				1.5		
Plateau Voltage	$V_{GP}$				3		V
Total Gate Charge	Q <sub>G(TOT)</sub>				4		nC
SWITCHING CHARACTERISTICS (N	•		•		•		•
Turn-On Delay Time	t <sub>d(ON)</sub>				7		
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 4.5 V, V <sub>E</sub>	se = 64 V.		9		ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>	I <sub>D</sub> = 10 A, R <sub>G</sub>	$= 2.5 \Omega$		12		
Fall Time	t <sub>f</sub>				4		
DRAIN-SOURCE DIODE CHARACTE	ERISTICS		•		•		•
Forward Diode Voltage	$V_{SD}$	$V_{0.0} = 0 \text{ V}$ $T_{J} = 25^{\circ}\text{C}$	T <sub>J</sub> = 25°C		0.82	1.2	
		$V_{GS} = 0 \text{ V},$ $I_{S} = 5 \text{ A}$ $T_{J} = 125^{\circ}\text{C}$			0.68		V
Reverse Recovery Time	t <sub>RR</sub>		1		25		
Charge Time	ta	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/μs, I <sub>S</sub> = 10 A			17		ns
Discharge Time	t <sub>b</sub>				8		
Reverse Recovery Charge	Q <sub>RR</sub>	1			17		nC
	1						

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

6. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

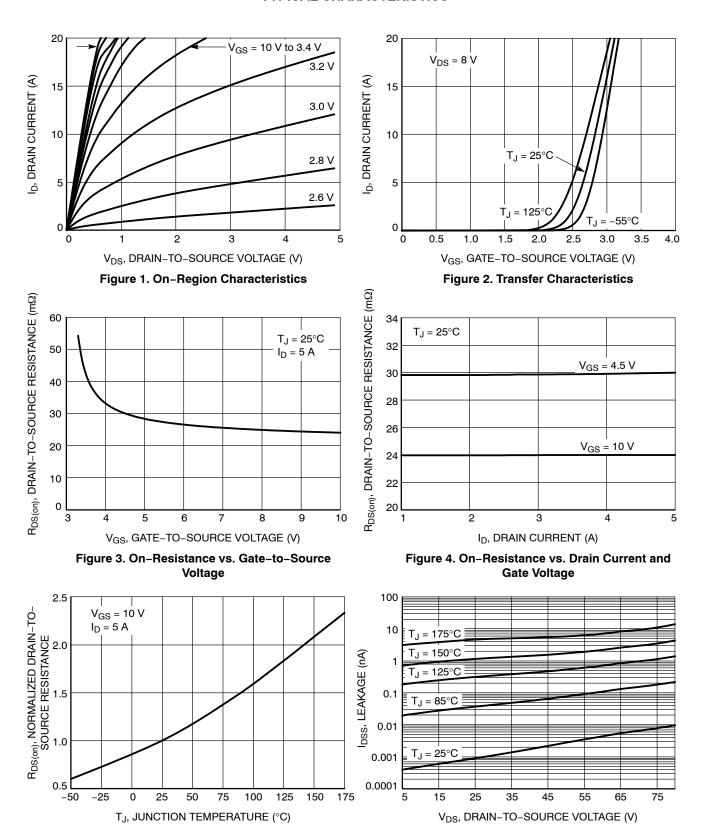


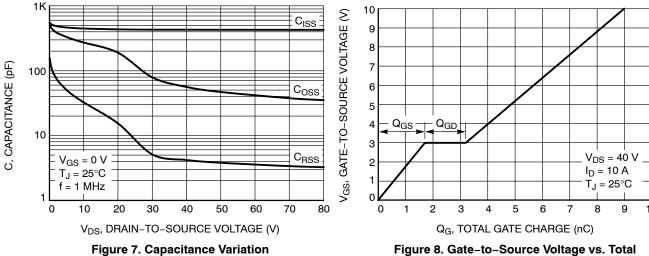
Figure 6. Drain-to-Source Leakage Current

vs. Voltage

Figure 5. On-Resistance Variation with

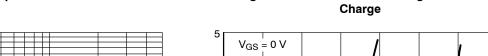
**Temperature** 

#### **TYPICAL CHARACTERISTICS**



IS, SOURCE CURRENT (A)

Figure 7. Capacitance Variation



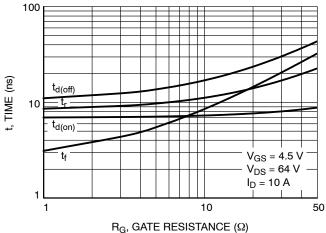


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

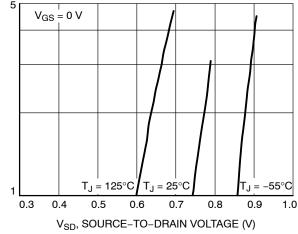


Figure 10. Diode Forward Voltage vs. Current

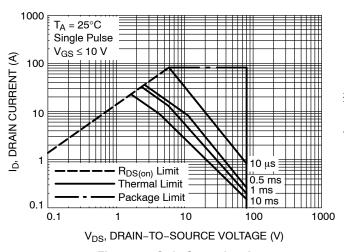


Figure 11. Safe Operating Area

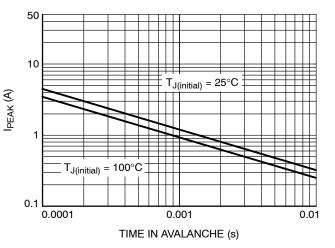


Figure 12. Maximum Drain Current vs. Time in **Avalanche** 

#### **TYPICAL CHARACTERISTICS**

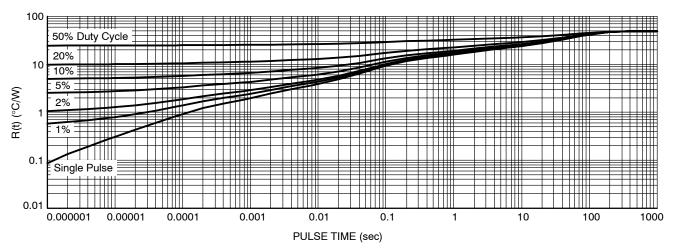


Figure 13. Thermal Response

#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NVTFS6H880NLTAG	880L	WDFN8 (Pb-Free)	1500 / Tape & Reel
NVTFS6H880NLWFTAG	80LW	WDFN8 (Pb-Free, Wettable Flanks)	1500 / Tape & Reel

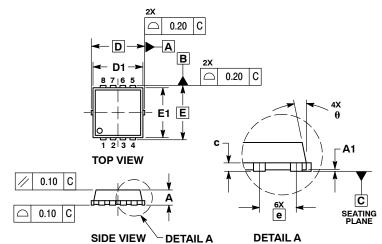
<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.





#### WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D

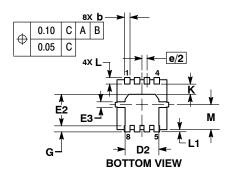
**DATE 23 APR 2012** 



#### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETERS.
  DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH
  PROTRUSIONS OR GATE BURRS.

	MI	LLIMETE	RS		INCHES	
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	0.70	0.75	0.80	0.028	0.030	0.031
A1	0.00		0.05	0.000		0.002
b	0.23	0.30	0.40	0.009	0.012	0.016
С	0.15	0.20	0.25	0.006	0.008	0.010
D		3.30 BSC		C	.130 BSC	)
D1	2.95	3.05	3.15	0.116	0.120	0.124
D2	1.98	2.11	2.24	0.078	0.083	0.088
Е		3.30 BSC		C	.130 BSC	)
E1	2.95	3.05	3.15	0.116	0.120	0.124
E2	1.47	1.60	1.73	0.058	0.063	0.068
E3	0.23	0.30	0.40	0.009	0.012	0.016
е		0.65 BSC	;	Ú	0.026 BS	2
G	0.30	0.41	0.51	0.012	0.016	0.020
K	0.65	0.80	0.95	0.026	0.032	0.037
L	0.30	0.43	0.56	0.012	0.017	0.022
L1	0.06	0.13	0.20	0.002	0.005	0.008
M	1.40	1.50	1.60	0.055	0.059	0.063
θ	0 °		12 °	0 °		12 °

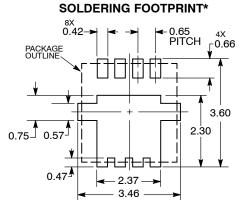


#### **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code Α = Assembly Location

= Year WW = Work Week = Pb-Free Package



DIMENSION: MILLIMETERS

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

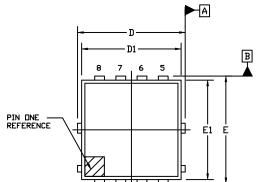
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<sup>\*</sup>This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

# WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF) CASE 515AN ISSUE O

**DATE 25 AUG 2020** 



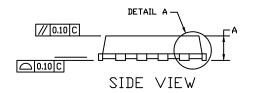
TOP VIEW

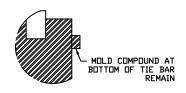


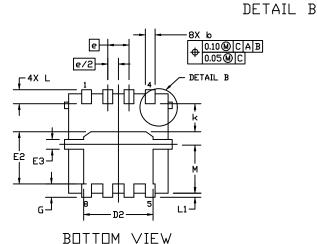
- 1. DIMENSIONING AND TOLERANCING PER.ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- DIMENSION D1 AND E1 D0 NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

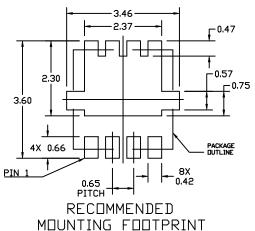
	ATED AREA
DETAIL A	C SEATING

	MILLIMETERS				
DIM	MIN.	NDM.	MAX.		
Α	0.70	0.75	0.80		
A1	0.00		0.05		
b	0.23	0.30	0.40		
С	0.15	0.20	0.25		
D	3.05	3.30	3.55		
D1	2.95	3.05	3.15		
D2	1.98	2.11	2.24		
Ε	3.05	3.30	3.55		
E1	2.95	3.05	3.15		
E2	1.47	1.60	1.73		
E3	0.23	0.30	0.40		
e		0.65 BSC			
G	0.30	0.41	0.51		
K	0.65	0.80	0.95		
L	0.30	0.43	0.59		
L1	0.06	0.13	0.20		
М	1.40	1.50	1.60		









\* For additional information on our Pb-Free strategy and soldering details, please download the IIN Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

# GENERIC MARKING DIAGRAM\*

XXXX AYWW• XXXX = Specific Device Code

A = Assembly Location

Y = Year

WW = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

(Note: Microdot may be in either location)

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DESCRIPTION:	WDFNW8 3.3x3.3, 0.65P (F	WDFNW8 3.3x3.3, 0.65P (Full-Cut μ8FL WF)		

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